

ShenZhen Renice Technology Co., Ltd

X5 2.5" PATA IDE SSD

Datasheet



V1.1

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1. INTRODUCTION

1.1 Product Overview

Based on NAND Flash technology Memory, Renice X5 2.5" IDE SSD (Solid State Drive) is a storage device with high performance and high reliability. Equipped with powerful Error Correction Coding (ECC) and flash interface, Renice X5 2.5" IDE SSD can support new generation NAND flash and keep much more stability in data transmission.

Renice X5 2.5" IDE SSD offers advanced technology to transfer data to the host via a high efficiency DMA engine and utilizes the internal memory buffer in a sufficient way. With Renice's optimized wear leveling, bad block management and flash management technologies, Renice X5 2.5" IDE SSD delivers extraordinary performance in data read/write speed and data reliability. Furthermore, with Internal detectors for power fail protection, over voltage and inrush current protection hardware design, Renice X5 2.5" IDE SSD can be a high-end IDE storage device for areas including industrial, automobile, military and medical, etc.

1.2 Feature

- Performance:
Read/Write: 118/109MB/s (@128GB)
- Form factor: 2.5-inch (100.0mm x 70.0mm x 9.5mm) LxWxH
- Interface standard: 44 PIN PATA IDE
- Density: 8GB, 16GB, 32GB, 64GB, 128GB
- Input voltage: 5.0V ($\pm 5\%$)
- Industrial operating temperature range from -40°C to +85°C
- Flash management algorithm: static and dynamic wear-leveling, bad block management algorithm.
- Supports dynamic power management and SMART (Self-Monitoring, Analysis and Reporting Technology).
- Internal detectors for power fail protection and Over voltage and inrush current protection hardware design.
- Hardware BCH ECC capable of correcting errors up to 72-bit/1KB
- Write endurance: >8 years @ 100GB write/day (8GB SLC SSD)
- Read endurance: unlimited
- Data retention: JESD47 compliant
- MTBF: 3,000,000 Hours

2. Functional Block Diagram

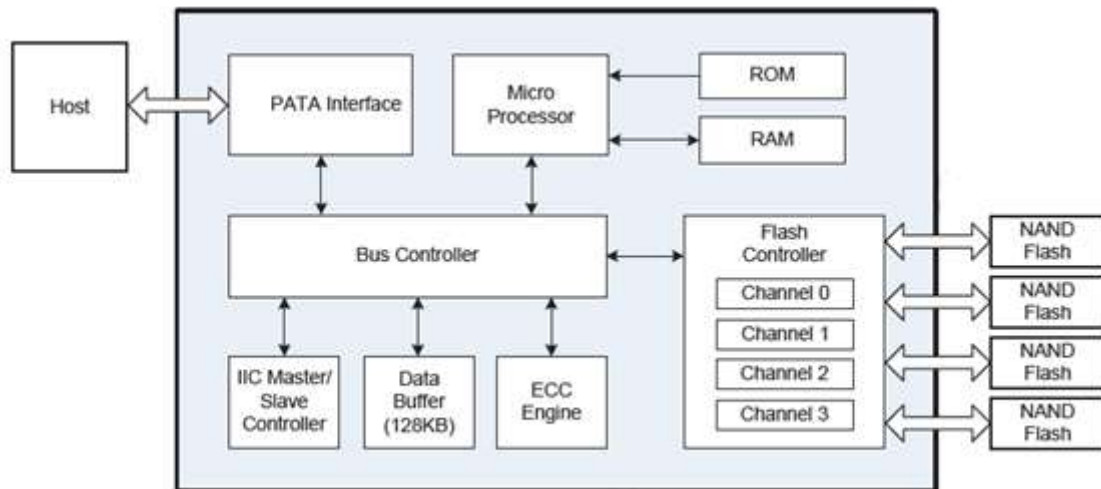


Figure 1: Block Diagram

3. Product Specifications

3.1 Physical Specifications

Form factor		2.5 inch
Dimensions(mm)	Length	100.00±0.40
	Width	70.00±0.20
	Height	9.50±0.15
Weight		<70g
Connector		44pin PATA connector

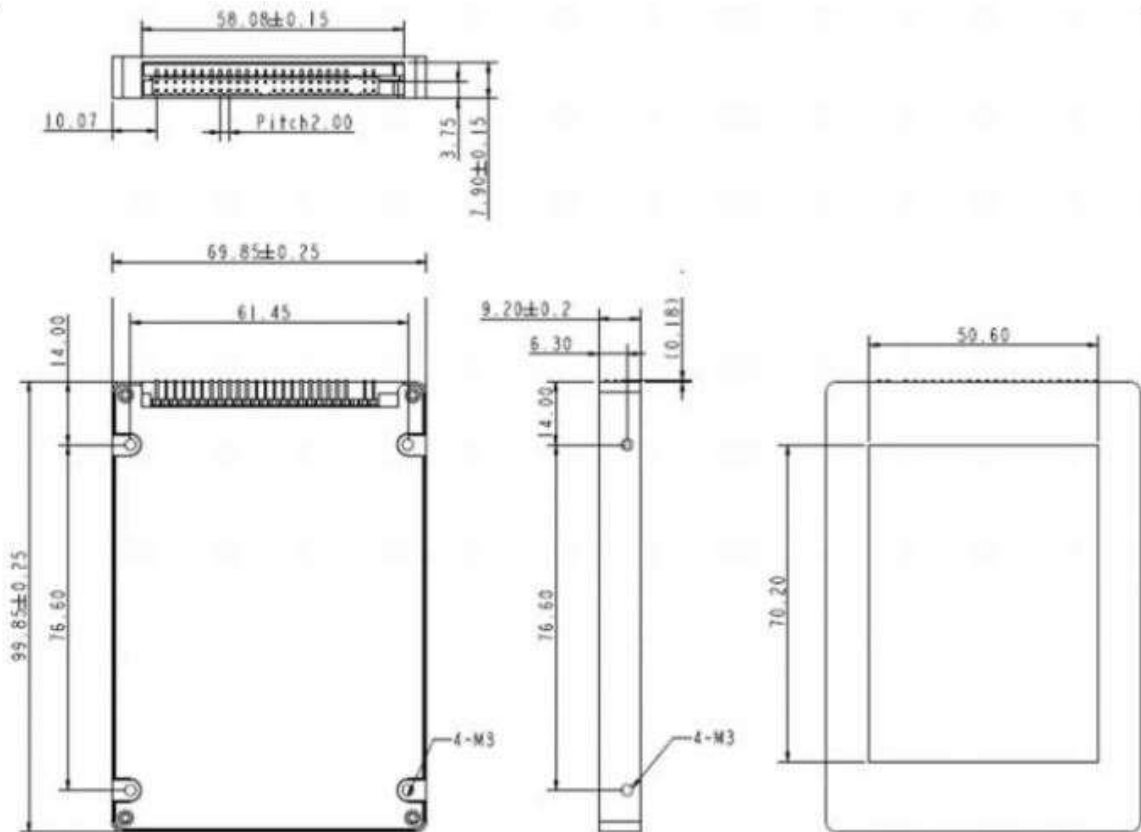


Figure 2: Mechanical Diagram

3.2 Host Interface

Host Interface

- Compliant with ATA/ATAPI-8
- Supports PIO Mode 0 - 6
- Supports Multiword DMA Mode 0 - 4
- Supports Ultra DMA Mode 0 - 7
- Supports PCMCIA Extended Memory Mode (cycle time: 250, 120, 100, 80 ns) with PCMCIA Ultra DMA Mode 0 - 7
- Supports TRIM command

3.3 Internal detectors for power fail protection

- Built-in 1.2V power-on reset
- Built-in 2.7V voltage detectors for power fail protection

4. Interface Description

4.1 Pin Assignment

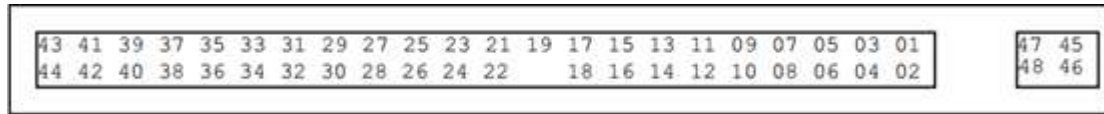


Figure 3: Pin Assignment

4.2 Pin Description

Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name
1	RESET	14	D13	27	IORDY	40	GND
2	GND	15	D1	28	CSEL	41	VCC35I
3	D7	16	D14	29	DMACK	42	VCC35I
4	D8	17	D0	30	GND	43	GND
5	D6	18	D15	31	INTRQ	44	NC
6	D9	19	GND	32	NC	45	GND
7	D5	20	NC	33	A1	46	CCSEL
8	D10	21	DMARQ	34	DIAG	47	NC
9	D4	22	GND	35	A0	48	CSEL
10	D11	23	IOWR	36	A2		
11	D3	24	GND	37	CS0		
12	D12	25	IORD	38	CS1		
13	D2	26	GND	39	DASP		

4.3 Master/ Slave settings instructions

Master disk: No connect

Slave disk: Connect 45 and 46

CableSelect: Connect 48 and 46

5. Electric Specifications

This chapter contains preliminary information and may be updated in a later version.

5.1 DC Characteristics

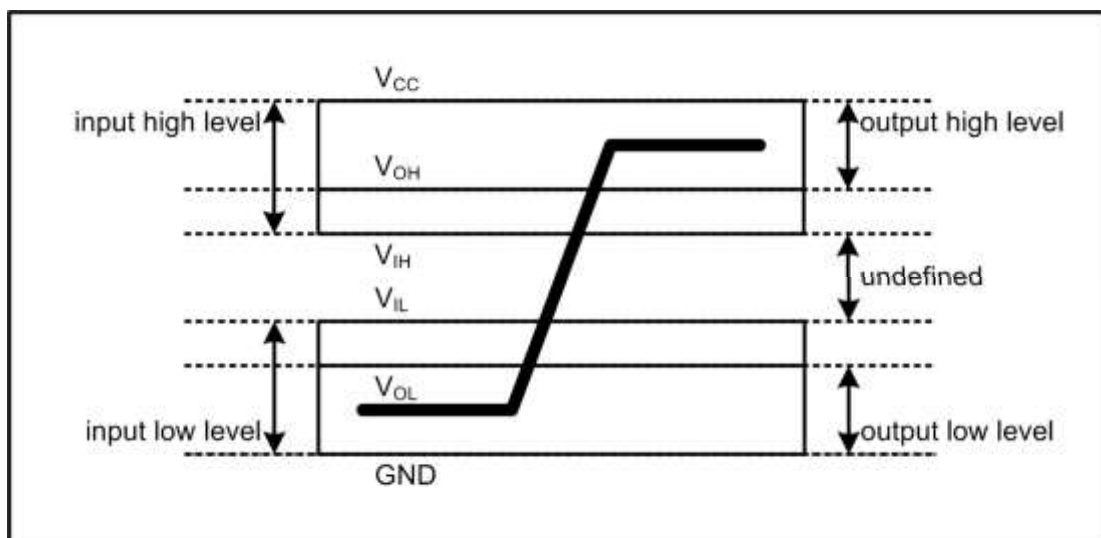


Figure 4: Bus Signal Level

DC Characteristics for Host Interface ($V_{CC} = 5V$)

Parameter	Symbol	Min	Max	Unit	Remark
Supply Voltage	VCC	4.5	5.5	V	
High Level Output Voltage	VOH	VCC - 0.8		V	
Low Level Output Voltage	VOL		0.8	V	
High Level Input Voltage	VIH	4.0		V	Non-schmitt trigger
		2.92		V	Schmitt trigger[1]
Low Level Input Voltage	VIL		0.8	V	Non-schmitt trigger
			1.70	V	Schmitt trigger[1]
Pull-Up Resistance	RPU	50	73	kΩ	
Pull-Down Resistance	RPD	50	97	kΩ	

DC Characteristics for Host Interface ($V_{CC} = 3.3V$)

Parameter	Symbol	Min	Max	Unit	Remark
Supply Voltage	VCC	2.97	3.63	V	
High Level Output Voltage	VOH	VCC - 0.8		V	
Low Level Output Voltage	VOL		0.8	V	
High Level Input Voltage	VIH	2.4		V	Non-schmitt trigger
		2.05		V	Schmitt trigger[1]
Low Level Input Voltage	VIL		0.6	V	Non-schmitt trigger
			1.25	V	Schmitt trigger[1]
Pull-Up Resistance	RPU	52.7	141	kΩ	
Pull-Down Resistance	RPD	47.5	172	kΩ	

The I/O Pins other than Host Interface

Parameter	Symbol	Min	Max	Unit	Remark
Supply Voltage	VCC	2.7	3.6	V	
High Level Output Voltage	VOH	2.4		V	
Low Level Output Voltage	VOL		0.4	V	
High Level Input Voltage	VIH	2.0		V	Non-schmitt trigger
		1.4	2.0	V	Schmitt trigger[1]
Low Level Input Voltage	VIL		0.8	V	Non-schmitt trigger
		0.8	1.2	V	Schmitt trigger[1]
Pull-Up Resistance	RPU	40		kΩ	
Pull-Down Resistance	RPD	40		kΩ	

Notes:

^[1] Include CE1#, CE2#, HREG#, HOE#, HIOE#, HWE#, HIOW# pins.

^[2] Include RST#, T0, T1, and T2 pin.

5.2 Internal IP Characteristics

1.2V Power On Reset

Parameter		Min	Max	Unit
Detect Voltage			1.3	V
Operating Voltage Range		0	1.65	V
Delay Time	Rise		4.5	μs
	Fall		2	μs

2.7V Voltage Detector

Parameter		Min	Max	Unit
Detect Voltage Range	VRR	1.4	2.9	V
	VFR	1.3	2.8	V
Delay Time	Rise		4.5	us
	Fall		1.5	us

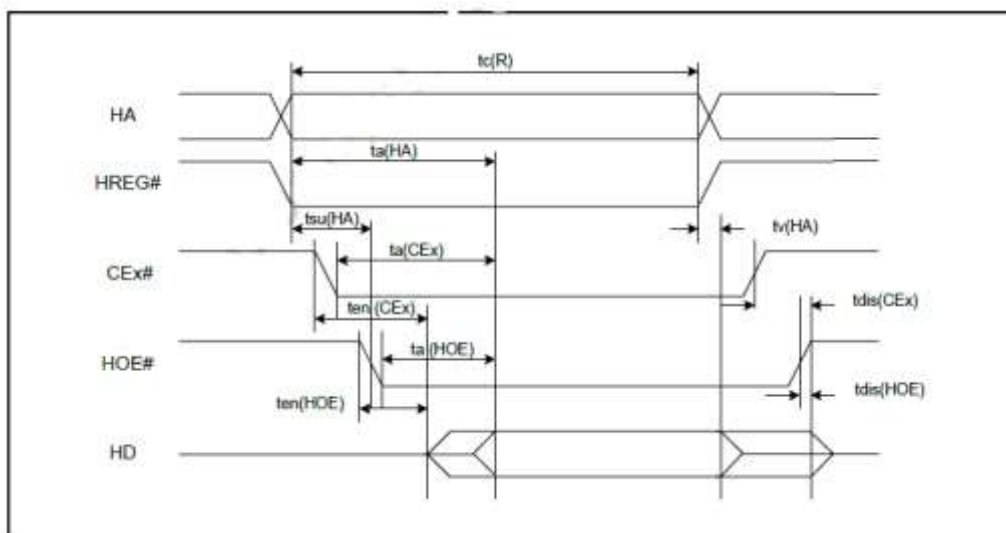
5.3 AC Characteristics

Attribute Memory Read Timing

Speed Version		300 ns		Unit
Item	Symbol	Min	Max	
Read Cycle Time	tc(R)	300		ns
Address Access Time	ta(HA)		300	ns
Card Enable Access Time	ta(CEx)		300	ns
Output Enable Access Time	ta(HOE)		150	ns
Output Disable Time from CEx#	tdis(CEx)		100	ns
Output Disable Time from HOE#	tdis(HOE)		100	ns
Address Setup Time	tsu(HA)	30		ns
Output Enable Time from CEx#	ten(CEx)	5		ns
Output Enable Time from HOE#	ten(HOE)	5		ns
Data Valid from Address Change	tv(HA)	0		ns

Note: All time intervals are recorded in nanoseconds. HD refers to data provided by the PATA Card to the system. The CEx# signal or both the HOE# signal and the HWE# signal are deasserted between consecutive cycle operations.

Figure 5: Attribute Memory Read Timing

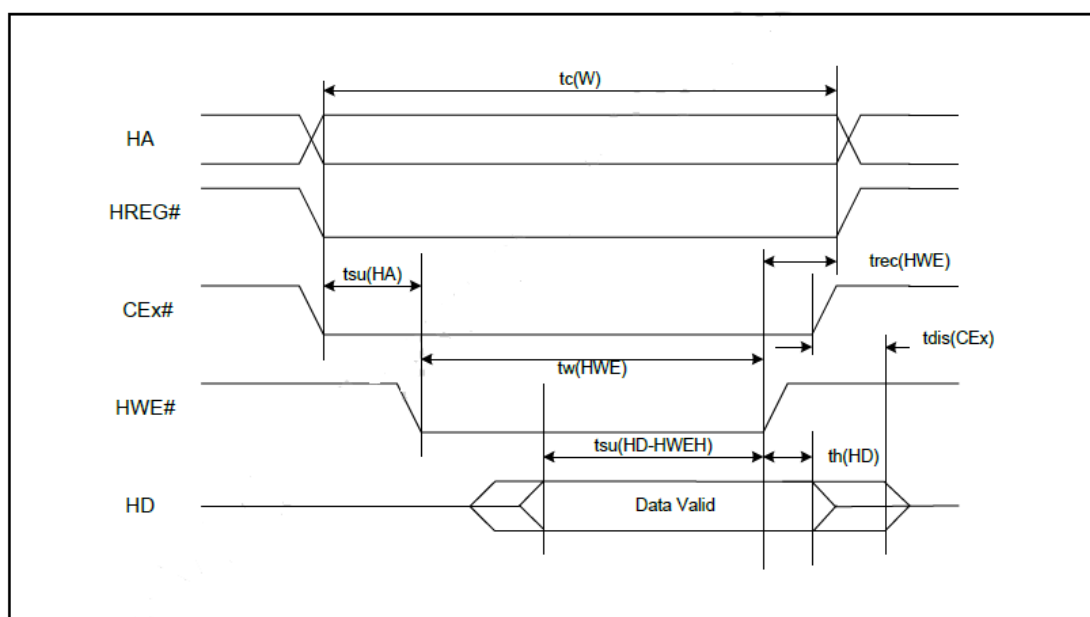


Configuration Register (Attribute Memory) Write Timing

Speed Version		250 ns		Unit
Item	Symbol	Min	Max	
Write Cycle Time	tc(W)	250		ns
Write Pulse Width	tw(HWE)	150		ns
Address Setup Time	tsu(HA)	30		ns
Write Recovery Time	trec(HWE)	30		ns
Data Setup Time for HWE#	tsu(HD-HWEH)	80		ns
Data Hold Time	th(HD)	30		ns

Note: All time intervals are recorded in nanoseconds. HD refers to data provided by the system to the PATA Card.

Figure 6: Configuration Register (Attribute Memory) Write Timing



Common Memory Read Timing

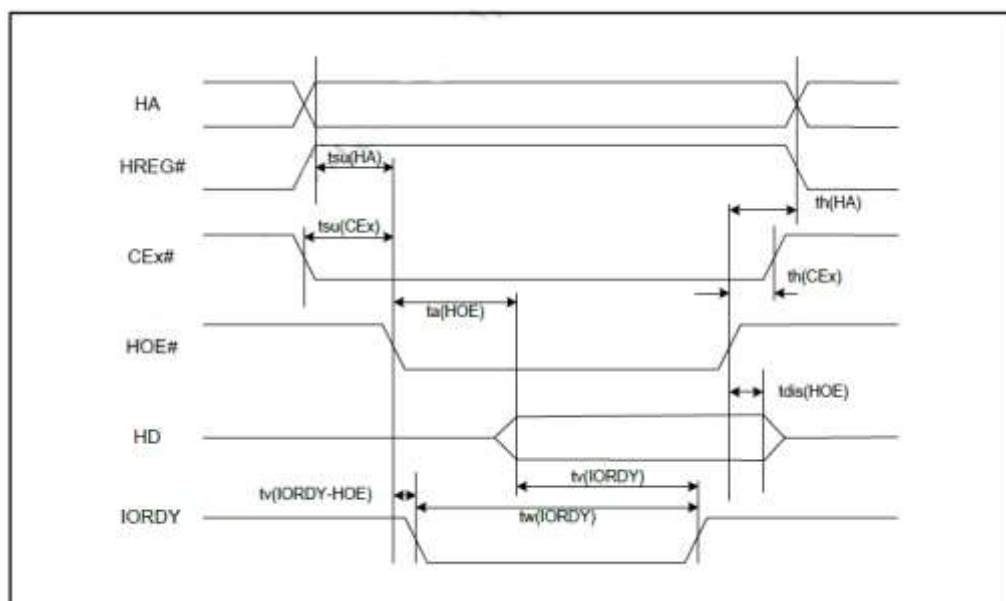
Cycle Time Mode		250 ns		120ns		100ns		80ns		Unit
Item	Symbol	Min	Max	Min	Max	Min	Max	Min	Max	
Output Enable Access Time	ta(HOE)		125		60		50		45	ns
Output Disable Time from HOE#	tdis(HOE)		100		60		50		45	ns
Address Setup Time	tsu(HA)	30		15		10		10		ns
Address Hold Time	t th(HA)	20		15		15		10		ns
CE# Setup before HOE#	tsu(CE#)	0		0		0		0		ns
CE# Hold following HOE#	th(CE#)	20		15		15		10		ns
Wait Delay Falling from HOE# tv	tv(IORDY-HOE)		35		35		35		na ^[1]	ns
Data Setup for Wait Release	tv(IORDY)		0		0		0		na ^[1]	ns
Wait Width Time ^[2]	tw(IORDY)		350		350		350		na ^[1]	ns

Notes:

^[1] IORDY is not supported in this mode.

^[2] The maximum load on IORDY is 1 LSTTL with a 50 pF (40 pF below 120 nsec cycle time) total load. All time intervals are recorded in nanoseconds. HD refers to data provided by the PATA Card to the system. The IORDY signal can be ignored when the HOE# cycle-to-cycle time is greater than the Wait Width time. The Max Wait Width time can be determined from the Card Information Structure (CIS). Although adhering to the PCMCIA specification of 12 μ s, the Wait Width time is intentionally lower in this specification.

Figure 7: Common Memory Read Timing



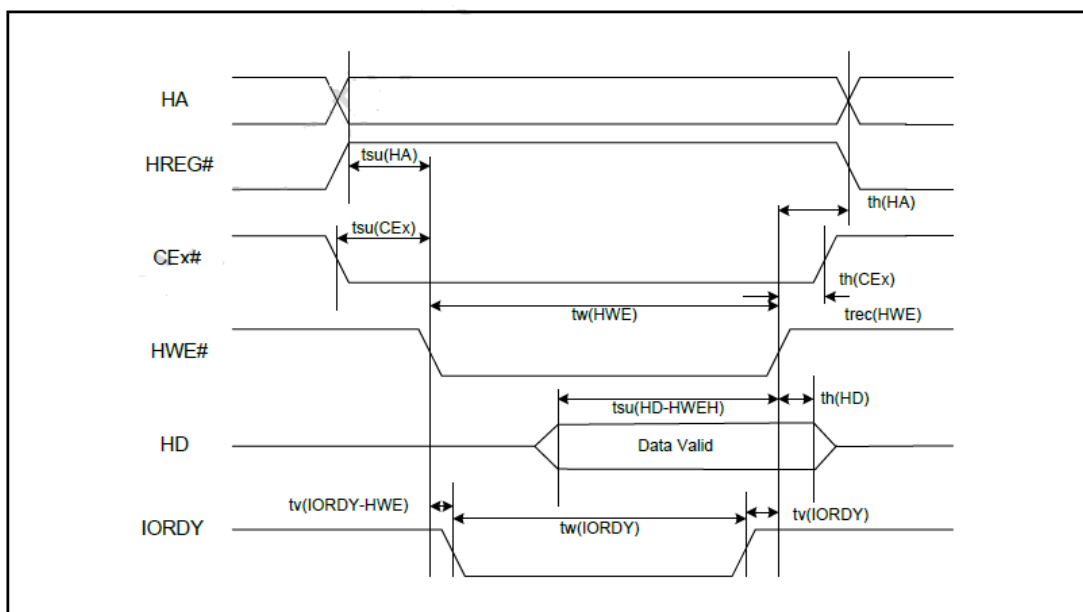
Common Memory Write Timing

Cycle Time Mode		250 ns		120ns		100ns		80ns		Unit
Item	Symbol	Min	Max	Min	Max	Min	Max	Min	Max	
Data Setup before HWE#	tsu(HD-HWEH)	80		50		40		30		ns
Data Hold following HWE#	th(HD)	30		15		10		10		ns
HWE# Pulse Width	tw(HWE)	150		70		60		55		ns
Address Setup Time	tsu(HA)	30		15		10		10		ns
CEx# Setup before HWE#	tsu(CEx)	0		0		0		0		ns
Write Recovery Time	Trec (HWE)	30		15		15		15		ns
Address Hold Time	th(HA)	20		15		15		15		ns
CEx# Hold following HWE#	th(CEx)	20		15		15		10		ns
Wait Delay Falling from HWE#	tv(IORDY-HWE)		35		35		35		na[1]	ns
HWE# High from Wait Release	Tv (IORDY)	0		0		0		na[1]		
Wait Width Time[2]	tw (IORDY)		350		350		350		na[1]	

Notes:

[1] IORDY is not supported in this mode.

[2] The maximum load on IORDY is 1 LSTTL with a 50 pF (40 pF below 120 nsec Cycle Time) total load. All time intervals are recorded in nanoseconds. HD refers to data provided by the PATA Card to the system. The IORDY signal can be ignored when the HWE# cycle-to-cycle time is greater than the Wait Width time. The Max Wait Width time can be determined from the Card Information Structure (CIS). Although adhering to the PCMCIA specification of 12 μ s, the Wait Width time is intentionally lower in this specification.

Figure 8: Common Memory Write Timing


I/O Read Timing

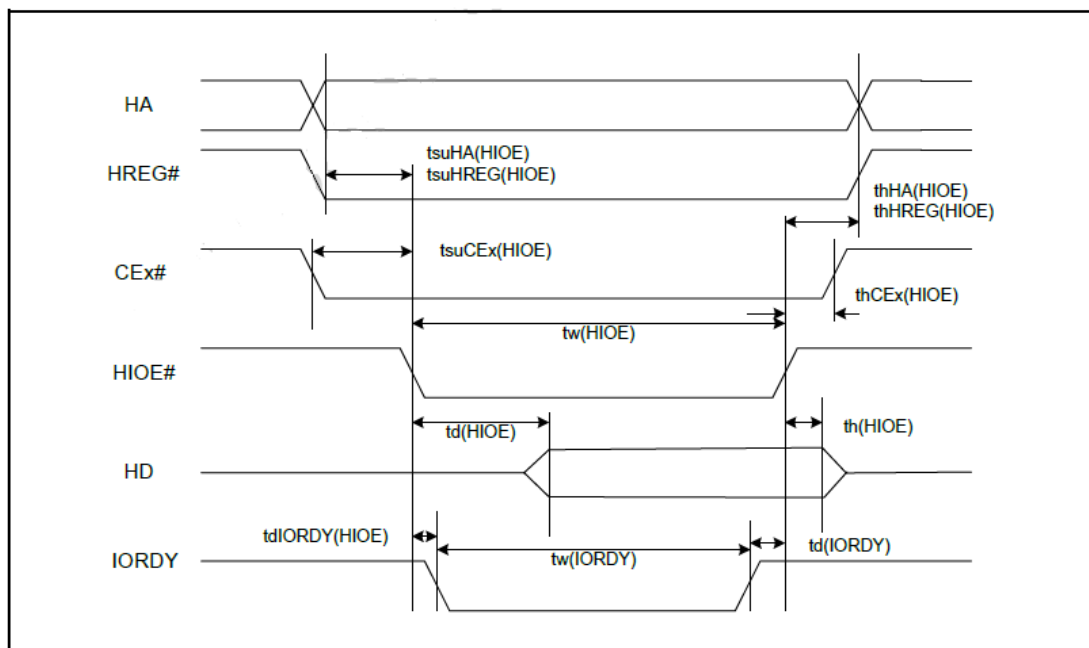
Cycle Time Mode		250 ns		120ns		100ns		80ns		Unit
Item	Symbol	Min	Max	Min	Max	Min	Max	Min	Max	
Data Delay after HIOE#	td(HIOE)		100		50		50		45	ns
Data Hold following HIOE#	th(HIOE)	0		5		5		5		ns
HIOE# Width Time	tw(HIOE)	165		70		65		55		ns
Address Setup before HIOE#	tsuHA (HIOE)	70		25		25		15		ns
Address Hold following HIOE#	thHA (HIOE)	20		10		10		10		ns
CEx# Setup before HIOE#	tsuCEx (HIOE)	5		5		5		5		ns
CEx# Hold following HIOE#	thCEx (HIOE)	20		10		10		10		ns
HREG# Setup before HIOE#	tsuHREG (HIOE)	5		5		5		5		ns
HREG# Hold following HIOE#	thHREG (HIOE)	0		0		0		0		ns
Wait Delay Falling from HIOE#[2]	tdIORDY (HIOE)		35		35		35		na[1]	
Data Delay from Wait Rising[2]	Td (IORDY)		0		0		0		na[1]	
Wait Width Time[2]	Tw (IORDY)		350		350		350		na[1]	

Notes:

[1] IORDY is not supported in this mode.

[2] Maximum load on IORDY is 1 LSTTL with a 50 pF (40 pF below 120 nsec cycle time) total load. All time intervals are recorded in nanoseconds. Although minimum time from IORDY high to HIOE# high is 0 nsec, the minimum HIOE# width is still met. HD refers to data provided by the PATA Card to the system. Although adhering to the PCMCIA specification of 12 μ s, the Wait Width time is intentionally lower in this specification.

Figure 9: I/O Read Timing



I/O Write Timing

Cycle Time Mode		250 ns		120ns		100ns		80ns		Unit
Item	Symbol	Min	Max	Min	Max	Min	Max	Min	Max	
Data Setup before HIOW#	tsu(HIOW)	60		20		20		15		ns
Data Hold following HIOW#	th(HIOW)	30		10		5		5		ns
HIOW# Width Time	tw(HIOW)	165		70		65		55		ns
Address Setup before HIOW#	tsuHA (HIOW)	70		25		25		15		ns
Address Hold following HIOW#	thHA (HIOW)	20		20		10		10		ns
CEx# Setup before HIOW#	tsuCEX (HIOW)	5		5		5		5		ns
CEx# Hold	thCEX	20		20		10		10		ns

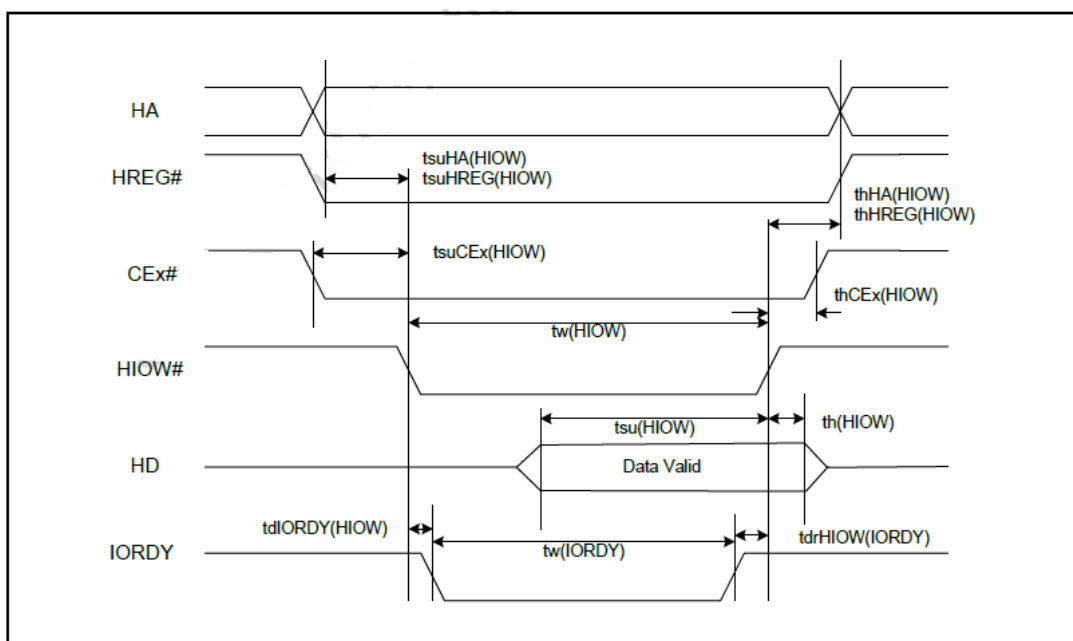
following HIOW#	(HIOW)									
HREG# Setup before HIOW#	tsuHREG (HIOW)	5		5		5		5		ns
HREG# Hold following HIOW#	thHREG (HIOW)	0		0		0		0		ns
Wait Delay Falling from HIOW#[2]	tdIORDY (HIOW)		35		35		35		na _[1]	ns
HIOW# high from Wait high[2]	tdrHIOW (IORDY)	0		0		0		na _[1]		ns
Wait Width Time[2]	Tw (IORDY)		350		350		350		na _[1]	ns

Notes:

[1] IORDY is not supported in this mode.

[2] The maximum load on IORDY is 1 LSTTL with a 50 pF (40 pF below 120 nsec cycle time) total load. All time intervals are recorded in nanoseconds. Although minimum time from IORDY high to HIOW# high is 0 nsec, the minimum HIOW# width is still met. HD refers to data provided by the PATA Card to the system. Although adhering to the PCMCIA specification of 12 μ s, the Wait Width time is intentionally lower in this specification.

Figure 10: I/O Write Timing



True IDE PIO Mode Read/Write Timing

	Item	Mode 0	Mode 1	Mode 2	Mode 3	Mode 4	Mode 5	Mode 6
t0	Cycle time (Min.) ^[1]	600	383	240	180	120	100	80
t1	Address valid to HIOE# / HIOW# setup (Min.)	70	50	30	30	25	15	10
t2	HIOE# / HIOW# (Min.) ^[1]	165	125	100	80	70	65	55
t2	HIOE# / HIOW# (Min.) Register (8-bit) ^[1]	290	290	290	80	70	65	55
t2i	HIOE# / HIOW# recovery time (Min.) ^[1]	-	-	-	70	25	25	20
t3	HIOW# data setup (Min.)	60	45	30	30	20	20	15
t4	HIOW# data hold (Min.)	30	20	15	10	10	10	5
t5	HIOE# data setup (Min.)	50	35	20	20	20	20	10
t6	HIOE# data hold (Min.)	5	5	5	5	5	5	5
t6Z	HIOE# data tristate (Max.) ^[2]	30	30	30	30	30	30	20
t7	Address valid to IOCS16# assertion (Max.) ^[4]	90	50	40	n/a	n/a	n/a	n/a
t8	Address valid to IOCS16# released (Max.) ^[4]	60	45	30	n/a	n/a	n/a	n/a
t9	HIOE# / HIOW# to address valid hold	20	15	10	10	10	10	10
tRD	Read Data valid to IORDY active (Min.), if IORDY initially low after tA	0	0	0	0	0	0	0
tA	IORDY Setup time ^[3]	35	35	35	35	35	na ^[5]	na ^[5]
tB	IORDY Pulse Width (Max.)	1250	1250	1250	1250	1250	na ^[5]	na ^[5]
tC	IORDY assertion to release (Max.)	5	5	5	5	5	na ^[5]	na ^[5]

Notes: All timings are in nanoseconds. The maximum load on IOCS16# is 1 LSTTL with a 50 pF (40 pF below 120 nsec cycle time) total load. All time intervals are recorded in nanoseconds. Although minimum time from IORDY high to HIOE# high is 0 nsec, the minimum HIOE# width is still met.

^[1] Where t0 denotes the minimum total cycle time; t2 represents the minimum command active time; t2i is the minimum command recovery time or command inactive time. Actual cycle time equals the sum of actual command active time and actual command inactive time. The three timing requirements for t0, t2, and t2i are met. The minimum total cycle time requirement is greater than the sum of t2 and t2i, implying that a host implementation can extend either or both t2 or t2i to ensure that t0 is equal to or greater than the value reported in the device's identity data. A PATA Card implementation supports any legal host implementation.

^[2] This parameter specifies the time from the negation edge of the HIOE# to the time that the PATA Card

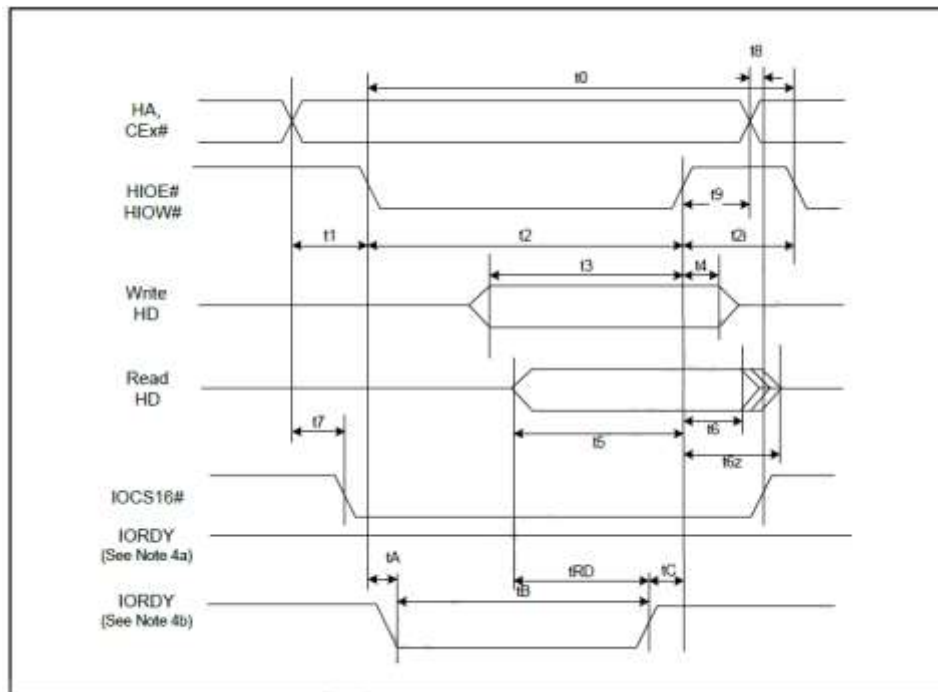
(tri-state) no longer drives the data bus.

[3] The delay originates from HIOE# or HIOW# activation until the state of IORDY is first sampled. If IORDY is inactive, the host waits until IORDY is active before the PIO cycle is completed. When the PATA Storage Card is not driving IORDY, which is negated at t_A after HIOE# or HIOW# activation, then t_5 is met and t_{RD} is inapplicable. When the PATA Card is driving IORDY, which is negated at the time t_A after HIOE# or HIOW# activation, then t_{RD} is met and t_5 is inapplicable.

[4] Both t_7 and t_8 apply to modes 0, 1, and 2 only. For other modes, this signal is invalid.

[5] IORDY is not supported in this mode.

Figure 11: True IDE Mode Read/Write Timing



Notes:

1. Device address comprises CE1#, CE2#, and HA[2:0].
2. Data comprises HD[15:0] (16-bit) or HD[7:0] (8-bit).
3. IOCS16# is shown for PIO modes 0, 1, and 2. For other modes, this signal is ignored.
4. The negation of IORDY by the device is used to lengthen the PIO cycle. Whether the cycle is to be extended is determined by the host after t_A from the assertion of HIOE# or HIOW#. The assertion and negation of IORDY is described in the following three cases.
 - (a) The device never negates IORDY: No wait is generated.
 - (b) Device drives IORDY low before t_A : a wait is generated. The cycle is completed after IORDY is reasserted. For cycles in which a wait is generated and HIOE# is asserted, the device places read data on D15-D00 for t_{RD} before IORDY is asserted.

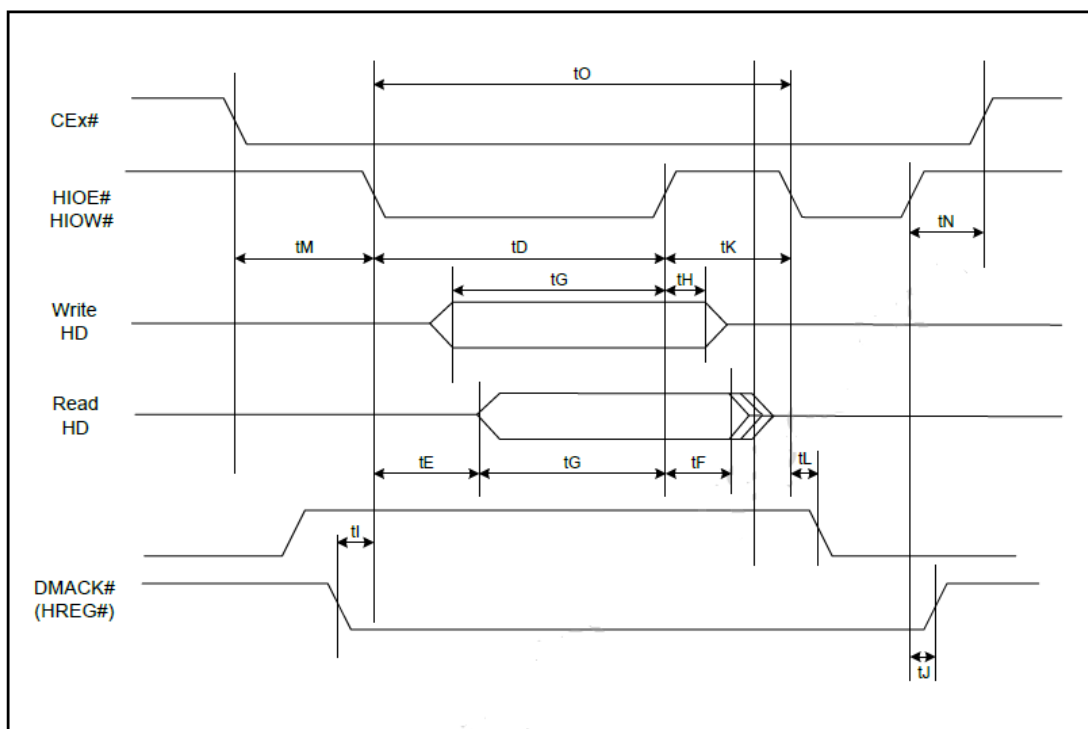
True IDE Multiword DMA Mode Read/Write Timing

	Item	Mode 0	Mode1	Mode 2	Mode3	Mode 4	Unit	Note
tO	Cycle time (Min.)	480	150	120	100	80	ns	[1]
tD	HIOE# / HIOW# asserted width (Min.)	215	80	70	65	55	ns	[1]
tE	HIOE# data access (Max.)	150	60	50	50	45	ns	
tF	HIOE# data hold (Min.)	5	5	5	5	5	ns	
tG	HIOE# / HIOW# data setup (Min.)	100	30	20	15	10	ns	
tH	HIOW# data hold (Min.)	20	15	10	5	5	ns	
tI	HREG# to HIOE# / HIOW# setup (Min.)	0	0	0	0	0	ns	
tJ	HIOE# / HIO50W# to HREG# hold (Min.)	20	5	5	5	5	ns	
tKR	HIOE# negated width (Min.)	50	50	25	25	20	ns	[1]
tKW	HIOW# 30negated width (Min.)	215	50	25	25	20	ns	[1]
tLR	HIOE# to DMARQ delay (Max.)	120	40	35	35	35	ns	
tLW	HIOW# to DMARQ delay (Max.)	40	40	35	35	35	ns	
tM	CEX# valid to HIOE# / HIOW#	50	30	25	10	5	ns	
tN	CEX# hold	15	10	10	10	10	ns	

Note:

[1] Where tO is the minimum total cycle time and tD is minimum command active time, whereas tKR and tKW are minimum command recovery time or command inactive time for input and output cycles, respectively. Actual cycle time equals the sum of actual command active time and actual command inactive time. The three timing requirements of tO, i.e. tD, tKR, and tKW, must be met. The minimum total cycle time requirement exceeds the sum of tD and tKR or tKW for input and output cycles, respectively, implying that a host implementation can extend either or both tD and tKR or tKW as deemed necessary to ensure that tO equals or exceeds the value reported in the device's identity data.

Figure 12: True IDE Multiword DMA Mode Read/Write Timing



Notes:

1. If a card cannot sustain continuous, minimum cycle time DMA transfers, it may negate DMARQ during the time from the start of a DMA transfer cycle (to suspend DMA transfers in progress) and reassertion of the signal at a relatively later time to continue DMA transfer operations.
2. The host may negate this signal to suspend the DMA transfer in progress.

Ultra DMA Signal Usage in Each Interface Mode

Signal	Type	(Non UDMA MEM MODE)	PC CARD MEM MODE UDMA	PC CARD IO MODE UDMA	TRUE IDE MODE UDMA
DMARQ	Output	(INPACK#)	DMARQ#	DMARQ#	DMARQ
HREG#	Input	(REG#)	DMACK#	DMACK	DMACK#
HIOV#	Input	(IOWR#)	STOP _[1]	STOP _[1]	STOP _[1]
HIOE#	Input	(IORD#)	HDMARDY#(R) _{[1][2]} HSTROBE(W) _{[1][3][4]}	HDMARDY#(R) _{[1][2]} HSTROBE(W) _{[1][3][4]}	HDMARDY#(R) _{[1][2]} HSTROBE(W) _{[1][3][4]}
IORDY	Output	(WAIT#)	DDMARDY#(W) _{[1][3]} DSTROBE(R) _{[1][2][4]}	DDMARDY#(W) _{[1][3]} DSTROBE(R) _{[1][2][4]}	DDMARDY#(W) _{[1][3]} DSTROBE(R) _{[1][2][4]}
HD[15:0]	Bidir	(D[15:00])	D[15:00]	D[15:00]	D[15:00]
HA[10:0]	Input	(A[10:00])	A[10:00]	A[10:00]	A[02:00] _[5]
CSEL#	Input	(CSEL#)	CSEL#	CSEL#	CSEL#
HIRQ	Output	(READY)	READY	INTRQ#	INTRQ
CE1# CE2#	Input	(CE1#) (CE2#)	CE1# CE2#	CE1# CE2#	CS0# CS1#

Notes:

- [1] UDMA interpretation of this signal is valid only during an Ultra DMA data burst.
- [2] UDMA interpretation of this signal is valid only during an Ultra DMA data burst during a DMA Read command.
- [3] UDMA interpretation of this signal is valid only during an Ultra DMA data burst during a DMA Write command.
- [4] HSTROBE and DSTROBE signals are active on both rising and falling edges.
- [5] Address lines 03-10 are not used in the True IDE mode.

Ultra DMA Data Burst Timing Requirements

Name	UDMA Mode 0		UDMA Mode 1		UDMA Mode 2		UDMA Mode3		UDMA Mode 4		UDMA Mode 5		UDMA Mode 6		UDMA Mode 7		Measure Location (see Note[2])
	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
t _{2CYCTYP}	240		160		120		90		60		40		30		24		Sender
t _{CYC}	112		73		54		39		25		16.8		13.0		10		Note[3]
t _{2CYC}	230		153		115		86		57		38		29		23		Sender
t _{DS}	15.0		10.0		7.0		7.0		5.0		4.0		2.6		2.5		Recipient
t _{DH}	5.0		5.0		5.0		5.0		5.0		4.6		3.5		2.9		Recipient
t _{DVS}	70.0		48.0		31.0		20.0		6.7		4.8		4.0		2.9		Sender
t _{DVH}	6.2		6.2		6.2		6.2		6.2		4.8		4.0		3.2		Sender
t _{CS}	15.0		10.0		7.0		7.0		5.0		5.0		5.0		5.0		Device
t _{CH}	5.0		5.0		5.0		5.0		5.0		5.0		5.0		5.0		Device
t _{CVS}	70.0		48.0		31.0		20.0		6.7		10.0		10.0		10.0		Host
t _{CVH}	6.2		6.2		6.2		6.2		6.2		10.0		10.0		10.0		Host
t _{ZFS}	0		0		0		0		0		35		25		15.0		Device
t _{DZFS}	70.0		48.0		31.0		20.0		6.7		25		17.5		10.5		Sender
t _{FS}		230		200		170		130		120		90		80		70	Device
t _{LI}	0	150	0	150	0	150	0	100	0	100	0	75	0	60		50	Note[4]
t _{MLI}	20		20		20		20		20		20		20		20		Host
t _{UI}	0		0		0		0		0		0		0		0		Host
t _{AZ}		10		10		10		10		10		10		10		10	Note[5]
t _{DAH}	20		20		20		20		20		20		20		20		Host
t _{AD}	0		0		0		0		0		0		0		0		Device
t _{ENV}	20	70	20	70	20	70	20	55	20	55	20	50	20	50	20	50	Host
t _{RFS}		75		70		60		60		60		50		50		50	Sender
t _{RP}	160		125		100		100		100		85		85		85		Host

t _{IOR}	20	20	20	20	20	20	20	20	20	20	20	20	20	20	20	Device
t _{ZIOR}	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	Device
t _{ACK}	20	20	20	20	20	20	20	20	20	20	20	20	20	20	20	Host
t _{SS}	50	50	50	50	50	50	50	50	50	50	50	50	50	50	50	Sender

Notes: All timings in ns:

- [1] All timing measurement switching points (low to high and high to low) are taken at 1.5V.
- [2] All signal transitions for a timing parameter are determined at the connector specified in the measurement location column. For instance, for the case of t_{RFS}, both STROBE and DMARDY# transitions are determined by the sender's connector.
- [3] Parameter t_{CYC} is determined at the connector of the recipient farthest from the sender.
- [4] Parameter t_{LI} is determined at the connector of a sender or recipient responding to an incoming transition from the recipient or sender, respectively. Both incoming signal and outgoing response are determined at the same connector.
- [5] Parameter t_{AZ} is determined at the connector of a sender or recipient driving the bus, and must release the bus to allow for a bus turnaround.
- [6] Table 25 lists the AC Timing requirements: Ultra DMA AC Signal Requirements.

Ultra DMA Data Burst Timing Descriptions

Name	Comment	Note
t _{2CYCTYP}	Typical sustained average two cycle time	
t _{CYC}	Cycle time allowing for asymmetry and clock variations (from STROBE edge to STROBE edge)	
t _{2CYC}	Two cycle time allowing for clock variations (from rising edge to next rising edge or from falling edge to next falling edge of STROBE)	[2][5]
t _{DS}	Data setup time at recipient (from data valid until STROBE edge)	[2][5]
t _{DH}	Data hold time at recipient (from STROBE edge until data may become invalid)	[3]
t _{DVS}	Data valid setup time at sender (from data valid until STROBE edge)	[3]
t _{DVH}	Data valid hold time at sender (from STROBE edge until data may become invalid)	[2]
t _{CS}	CRC word setup time at device	[2]
t _{CH}	CRC word hold time at device	[3]
t _{CVS}	CRC word valid setup time at host (from CRC valid until DMACK(##) negation)	[3]
t _{CVH}	CRC word valid hold time at sender (from DMACK(##) negation until CRC may become invalid)	
t _{ZFS}	Time from STROBE output released-to-driving until the first transition of critical timing.	
t _{DZFS}	Time from data output released-to-driving until the first transition of critical timing.	
t _{FS}	First STROBE time (for device to first negate DSTROBE from STOP during a data in burst)	[1]
t _{LI}	Limited interlock time	[1]

tMLI	Interlock time with minimum	[1]
tUI	Unlimited interlock time	
tAZ	Maximum time allowed for output drivers to release (from asserted or negated)	
tZAH	Minimum delay time required for output	
tZAD	drivers to assert or negate (from released)	
tENV	Envelope time (from DMACK(#) to STOP and HDMARDY# during data in burst initiation and from DMACK(#) to STOP during data out burst initiation)	
tRFS	Ready-to-final-STROBE time (no STROBE edges shall be sent this long after negation of DMARDY#)	
tRP	Ready-to-pause time (that recipient shall wait to pause after negating DMARDY#)	
tIORDYZ	Maximum time before releasing IORDY	[6]
tZIORDY	Minimum time before driving IORDY	[4][6]
tACK	Setup and hold times for DMACK(#) (before assertion or negation)	
tSS	Time from STROBE edge to negation of DMARQ(#) or assertion of STOP (when sender terminates a burst)	

Notes:

[1] Parameters tUI, tMLI (in Figure 16: Ultra DMA Data-In Burst Device Termination Timing and Figure 17: Ultra DMA Data-In Burst Host Termination Timing), and tLI represent sender-to-recipient or recipient-to-sender interlocks, i.e., one agent (sender or recipient) is waiting for the other agent to respond with a signal before proceeding. Parameter tUI denotes an unlimited interlock that has no maximum time value; tMLI represents a limited time-out that has a defined minimum; tLI is a limited time-out that has a defined maximum.

[2] The 80-conductor cabling is required to meet setup (tDS, tCS) and hold (tDH, tCH) times in modes exceeding 2.

[3] Timing for tDVS, tDVH, tCVS, and tCVH must be met for lumped capacitive loads of 15 and 40 pF at the connector where the data and STROBE signals have the same capacitive load value. Due to cable reflections, these timing measurements are invalid in a system functioning normally.

[4] For all timing modes, parameter tZIORDY may be greater than tENV since the host has a pull-up on IORDY giving it a known state when released.

[5] Parameters tDS and tDH for mode 5 are defined for a recipient at the end of a cable only in a configuration that has a single device located at the cable end. This configuration can result in tDS and tDH for mode 5 at the middle connector having minimum values of 3.0 and 3.9 ns, respectively.

[6] The parameters are applied to True IDE mode operation only.

Ultra DMA Sender and Recipient IC Timing Requirements

Name	UDMA Mode 0		UDMA Mode 1		UDMA Mode 2		UDMA Mode 3		UDMA Mode 4		UDMA Mode 5		UDMA Mode 6		UDMA Mode 7		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
tDSIC	14.7		9.7		6.8		6.8		4.8		2.3		2.3		2.3		ns
tDHIC	4.8		4.8		4.8		4.8		4.8		2.8		2.8		2.8		ns
tDVSIC	72.9		50.9		33.9		22.6		9.5		6.0		5.2		3.7		ns
tDVHIC	9.0		9.0		9.0		9.0		9.5		6.0		5.2		3.7		ns
tDSIC	Recipient IC data setup time (from data valid until STROBE edge) (see Note[2])																ns
tDHIC	Recipient IC data hold time (from STROBE edge until data may become invalid) (see Note[2])																ns
tDVSIC	Sender IC data valid setup time (from data valid until STROBE edge) (see Note[3])																ns
tDVHIC	Sender IC data valid hold time (from STROBE edge until data may become invalid) (see Note[3])																ns

Notes:

[1] All timing switching point measurements (low to high and high to low) are taken at 1.5V.

[2] The correct data value is captured by the recipient given input data with a slew rate of 0.4 V/ns rising and falling and the input STROBE with a slew rate of 0.4 V/ns rising and falling at tDSIC and tDHIC timing (as measured at 1.5V).

[3] Parameters tDVSIC and tDVHIC must be met for lumped capacitive loads of 15 and 40 pF at the IC where all signals have the same capacitive load value. Noise that can couple onto the output signals from external sources is not included in these values.

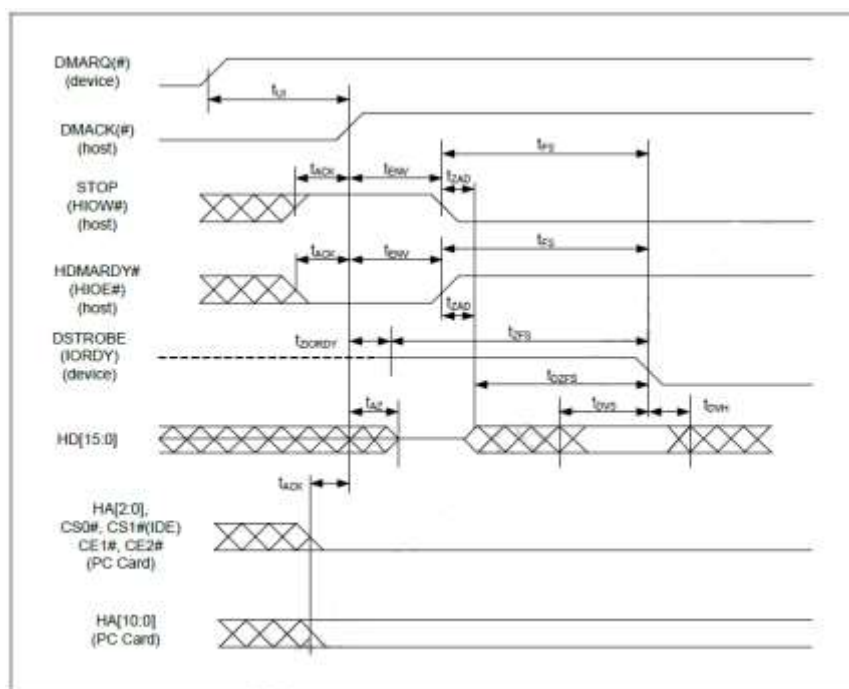
Ultra DMA AC Signal Requirements

Name	Comment	Min [V/ns]	Max [V/ns]	Note
SRISE	Rising Edge Slew Rate for any signal		1.25	[1]
SFALL	Falling Edge Slew Rate for any signal		1.25	[1]

Note:

[1] The sender is tested while driving an 18 inch, 80 conductor cable with PVC insulation. The signal being tested must be cut at a test point such that it has no trace, cable, or recipient loading after the test point. All other signals must remain connected through to the recipient. The test point should be located between a sender's series termination resistor and within 0.5 inch or less from where the conductor exits the connector. If the test point is on a cable conductor rather than the PCB, an adjacent ground conductor must also be cut within 0.5 inch of the connector. The test load and test points should be soldered directly to the exposed source side connectors. The test loads consist of a 15 pF or a 40 pF, 5%, 0.08 inch by 0.05 inch surface mount or relatively smaller capacitor connected between the test point and ground. Slew rates are met for both capacitor values. Measurements must be taken at the test point using a <1 pF, >100 Kohm, 1 Ghz probe and a 500 MHz oscilloscope. The average rate is measured from 20-80% of the settled VOH level with data transitions at least 120 nsec apart. The settled VOH level must be measured as the average high output level under the defined test conditions from 100 nsec after 80% of a rising edge until 20% of the subsequent falling edge.

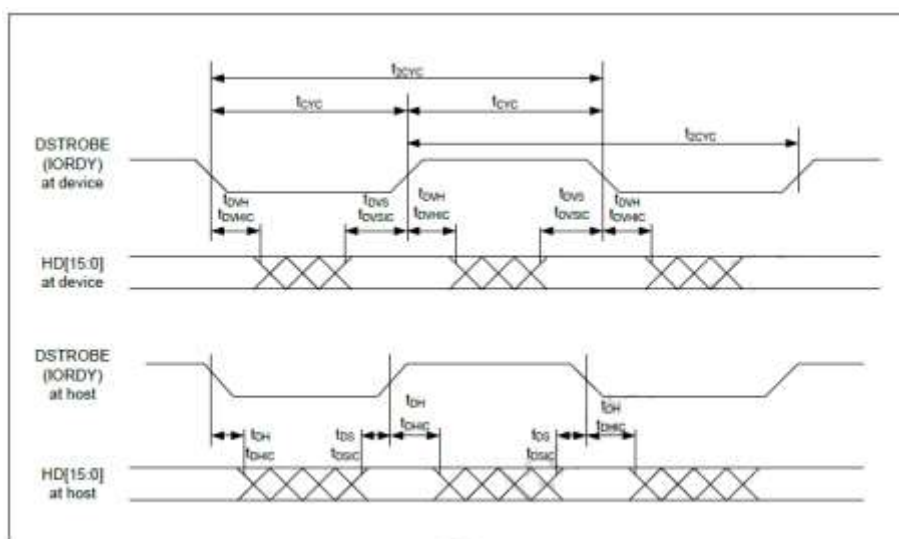
Figure 13: Ultra DMA Data-In Burst Initiation Timing



Notes:

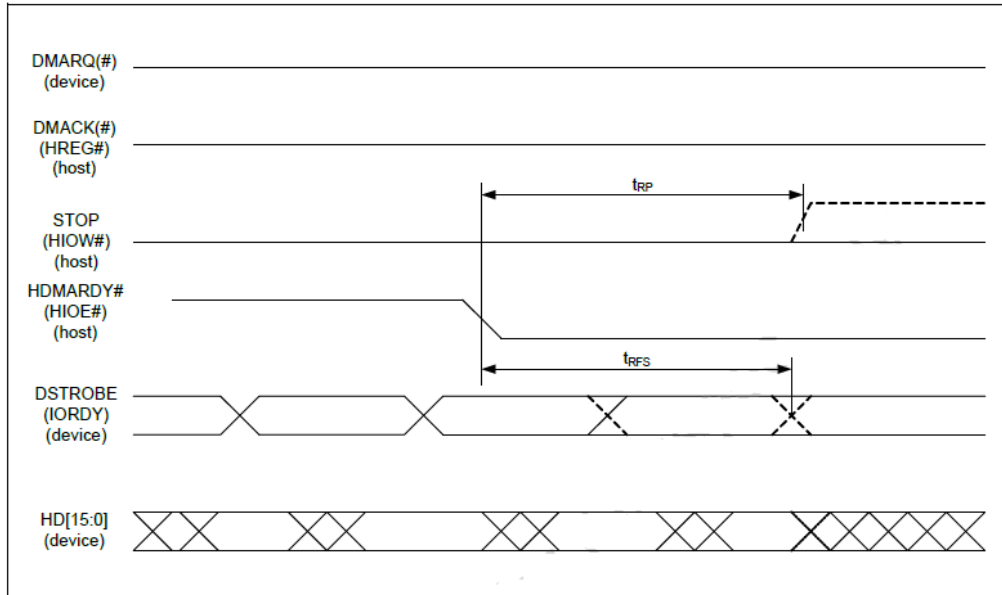
1. All waveforms in this diagram are shown with the asserted state high. Negative true signals are inverted on the bus relative to the diagram.
2. The definitions for the IORDY:DDMARDY#:DSTROBE, HIOE#: HDMARDY#: HSTROBE and HIOW#: STOP signal lines are not in effect until DMARQ(♯) and DMACK(♯) are asserted. Notably, HA[2:0], CS0♯ and CS1♯ are True IDE mode signal definitions, and HA[10:0], CE1♯ and CE2♯ are PC Card mode signals. The Bus polarity of DMACK(♯) and DMARQ(♯) is based on the active interface mode.

Figure 14: Sustained Ultra DMA Data-In Burst Timing



Note: HD[15:0] and IORDY signals are shown at both the host and device to emphasize that neither cable settling time nor cable propagation delay allow data signals to be considered stable at the host until after they are driven by the device.

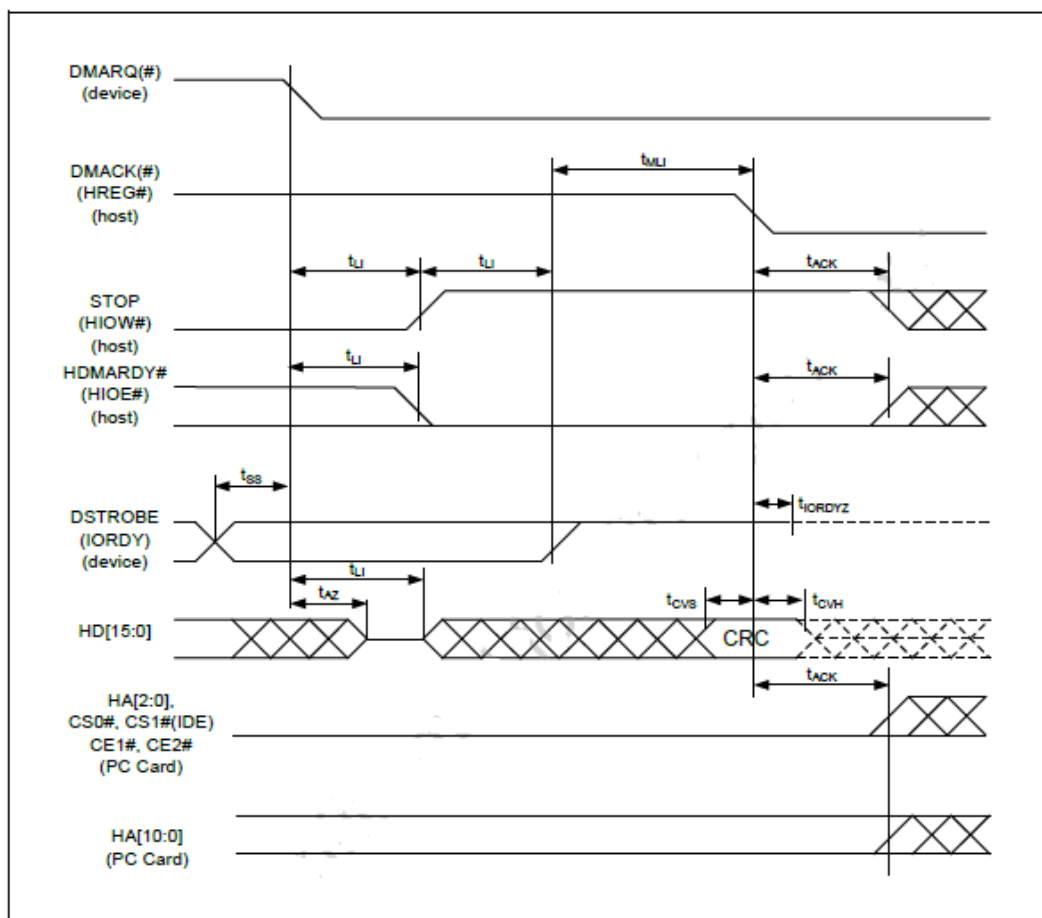
Figure 15: Ultra DMA Data-In Burst Host Pause Timing



Notes:

1. All waveforms in this diagram are shown with the asserted state high. Negative true signals are inverted on the bus relative to the diagram.
2. The host can implement STOP to request termination of the Ultra DMA data burst at a time no sooner than when t_{RP} after HDMARDY# is negated.
3. After negating HDMARDY#, the host may receive zero, 1, 2, or 3 additional data words from the device.
4. Bus polarities of the DMARQ(#) and DMACK(#) signals are dependent on the active interface mode.

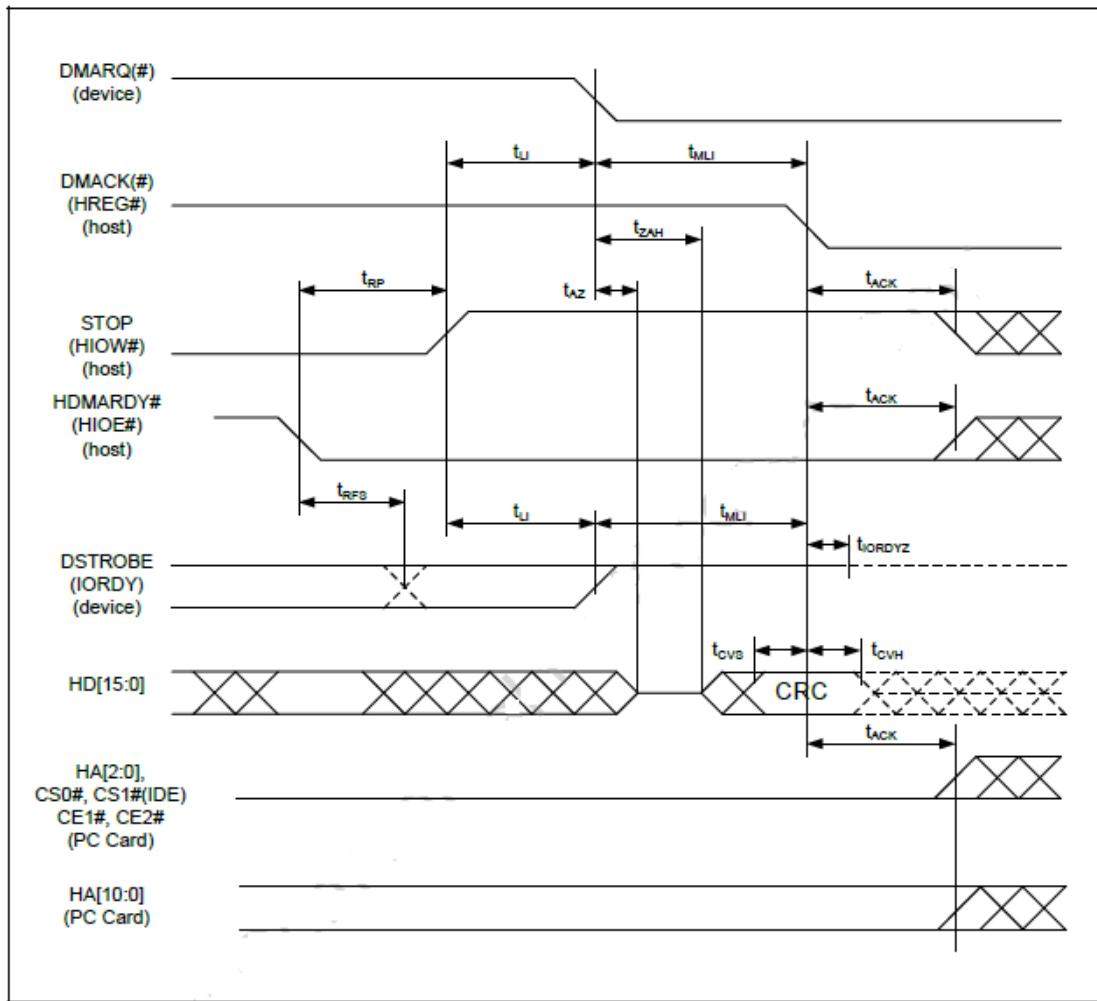
Figure 16: Ultra DMA Data-In Burst Device Termination Timing



Notes:

1. All waveforms in this diagram are shown with the asserted state high. Negative true signals are inverted on the bus relative to the diagram.
2. Definitions for STOP, HDMARDY##, and DSTROBE signal lines are no longer in effect once DMARQ(##) and DMACK(##) are negated. The HA[2:0], CS0## and CS1## are True IDE mode signal definitions. HA[10:0], CE1## and CE2## are PC Card mode signals. Bus polarities of DMARQ(##) and DMACK(##) are dependent on the active interface mode.

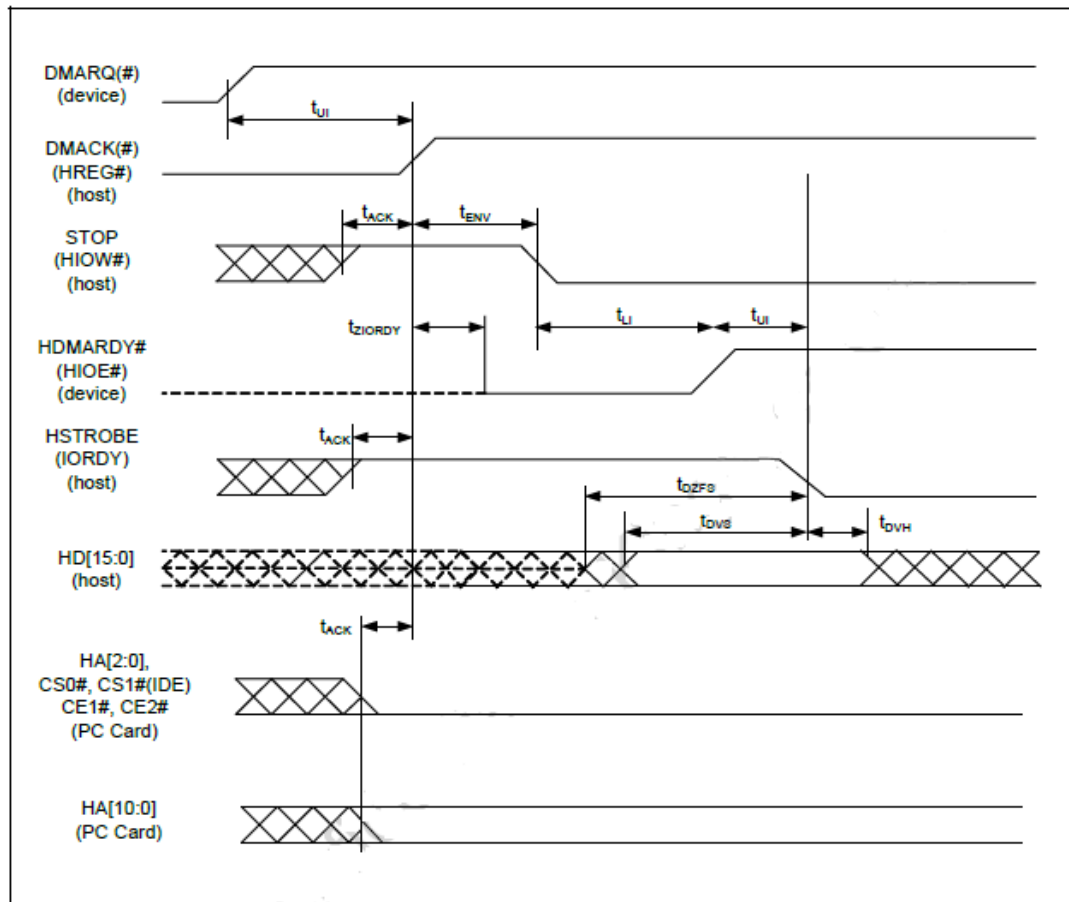
Figure 17: Ultra DMA Data-In Burst Host Termination Timing



Notes:

1. All waveforms in this diagram are shown with the asserted state high. Negative true signals are inverted on the bus relative to the diagram.
2. Definitions for STOP, HDMARDY##, and DSTROBE signal lines are no longer in effect once DMARQ(##) and DMACK(##) are negated. The HA[2:0], CS0## and CS1## are True IDE mode signal definitions. The HA[10:0], CE1## and CE2## are PC Card mode signal definitions. Bus polarities of DMARQ(##) and DMACK(##) are dependent on the active interface mode.

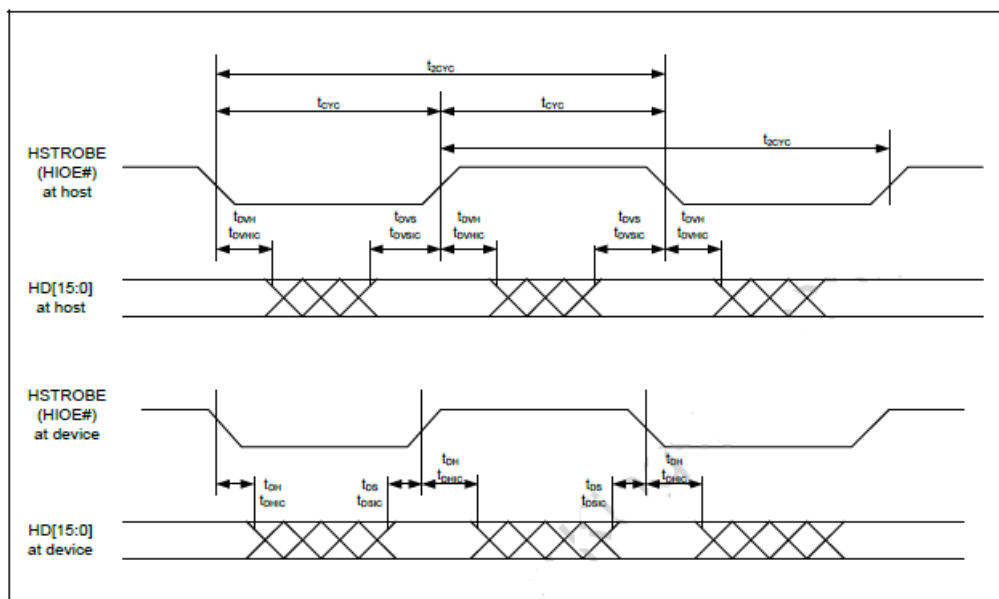
Figure 18: Ultra DMA Data-Out Burst Initiation Timing



Notes:

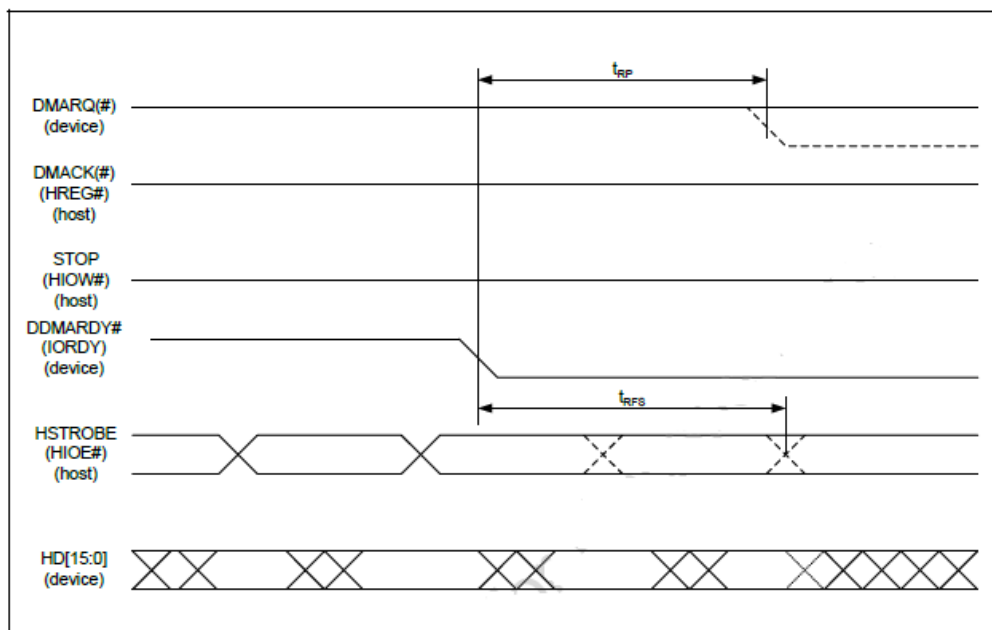
1. All waveforms in this diagram are shown with the asserted state high.
2. Negative true signals are inverted on the bus relative to the diagram.
3. Definitions for STOP, DDMARDY##, and HSTROBE signal lines are not in effect until the DMARQ(##) and DMACK(##) are asserted. The HA[2:0], CS0## and CS1## are True IDE mode signal definitions.
4. The HA[10:0], CE1## and CE2## are PC Card mode signal definitions. Bus polarities of DMARQ(##) and DMACK(##) are dependent on the active interface mode.

Figure 19: Sustained Ultra DMA Data-Out Burst Timing



Note: Data (HD[15:0]) and HSTROBE signals are shown at both the device and host to emphasize that neither cable settling time nor cable propagation delay allow for data signals to be considered stable at the device until after they are driven by a host.

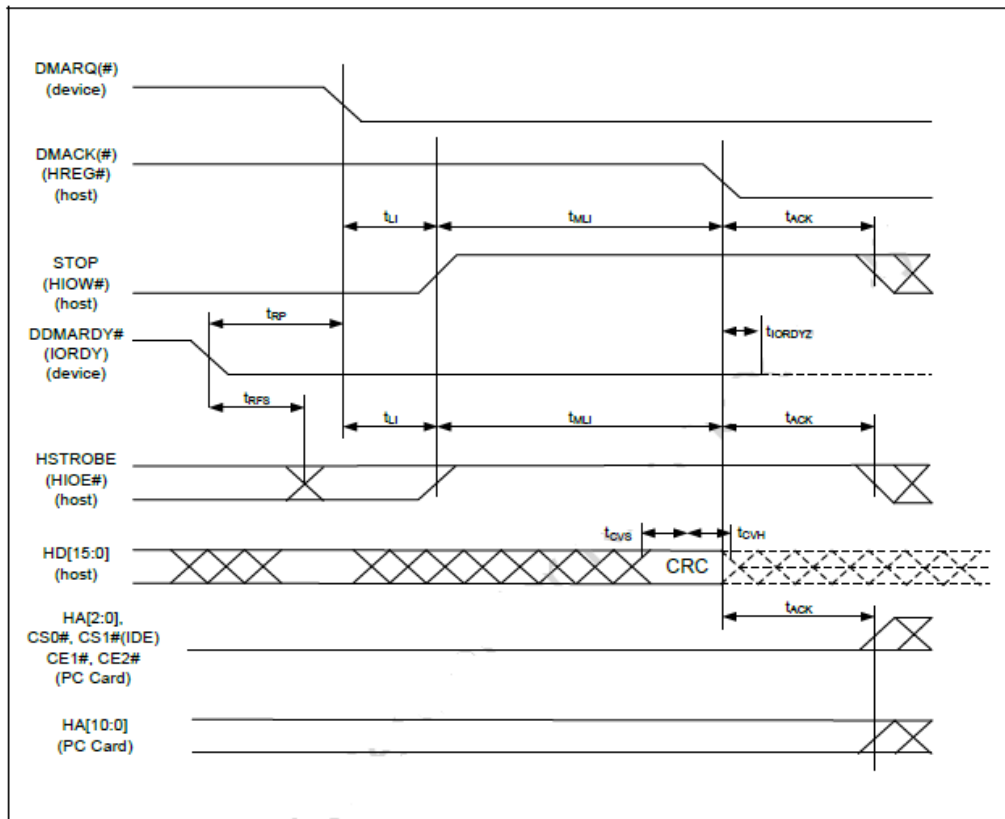
Figure 20: Ultra DMA Data-Out Burst Device Pause Timing



Notes:

1. All waveforms in this diagram are shown with the asserted state high. Negative true signals are inverted on the bus relative to the diagram. The device can negate DMARQ(0) when requesting termination of the Ultra DMA data burst no sooner than tRP after DDMARDY# is negated.
2. After negating DDMARDY#, the device may receive zero, 1, 2, or 3 additional data words from the host. The bus polarities of DMARQ(0) and DMACK(0) are dependent on the active interface mode.

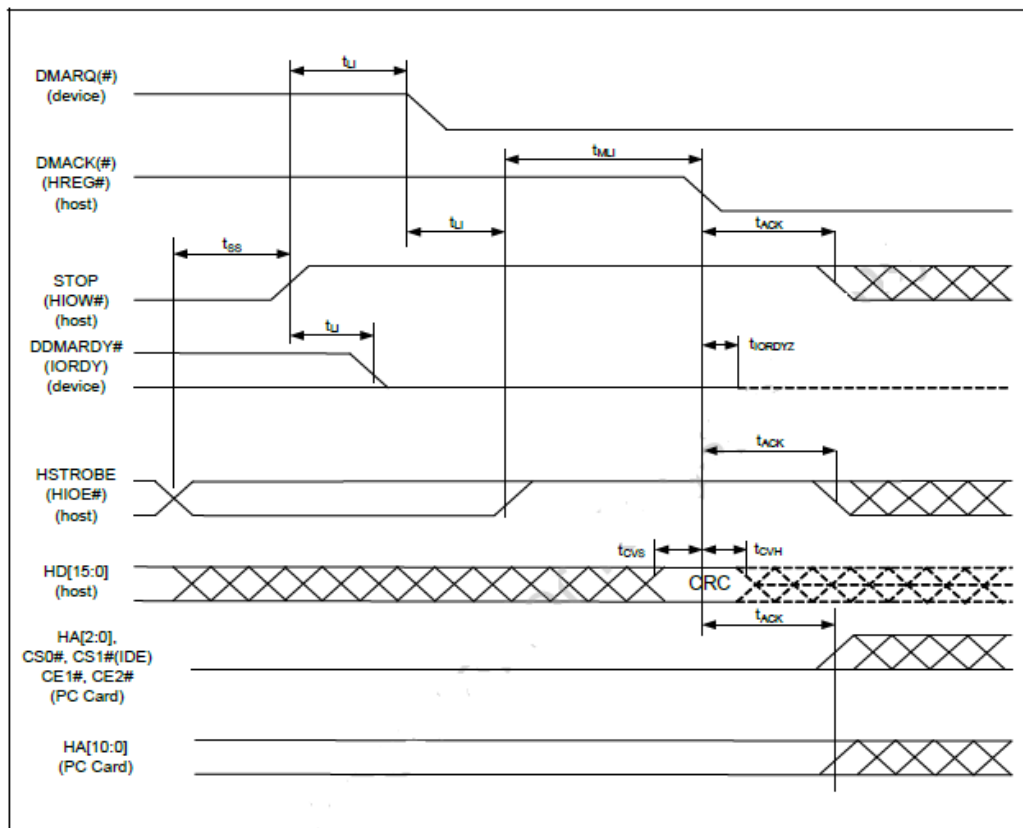
Figure 21: Ultra DMA Data-Out Burst Device Termination Timing



Notes:

1. All waveforms in this diagram are shown with the asserted state high. Negative true signals are inverted on the bus relative to the diagram.
2. Definitions for the STOP, DDMARDY##, and HSTROBE signal lines are no longer in effect [after OR once] DMARQ(##) and DMACK(##) are negated. The HA[2:0], CS0## and CS1## are True IDE mode signal definitions. The HA[10:0], CE1## and CE2## are PC Card mode signals. Bus polarities of DMARQ(##) and DMACK(##) are dependent on the active interface mode.

Figure 22: Ultra DMA Data-Out Burst Host Termination Timing



Notes:

1. All waveforms in this diagram are shown with the asserted state high. Negative true signals are inverted on the bus relative to the diagram.
2. Definitions for the STOP, DDMARDY##, and HSTROBE signal lines are no longer in effect once DMARQ(##) and DMACK(##) are negated. The HA[2:0], CS0## and CS1## are True IDE mode signal definitions. The HA[10:0], CE1## and CE2## are PC Card mode signal definitions. Bus polarities of DMARQ(##) and DMACK(##) are dependent on the active interface mode.

5.3.1 Flash Interface AC Characteristics

Flash Interface AC Timing Parameters for Command / Address

Symbol	Parameter	Timing		Unit
		Disable Flash CMD Extend	Enable Flash CMD Extend	
tCLS	CLE Setup Time	2	4	tCK
tCLH	CLE Hold Time	1	2	tCK
tALS	ALE Setup Time	2	4	tCK
tALH	ALE Hold Time	1	2	tCK
tWP	WE Pulse Width	1	2	tCK
tDS	Data Setup Time	1	3	tCK
tDH	Data Hold Time	1	1	tCK
tWC	Write Cycle Time	2	4	tCK
tWH	WE High Hold Time	1	2	tCK
tWP	WE Low Hold Time	1	2	tCK

Flash Interface AC Timing Parameters for Data

Symbol	Parameter	Timing	Unit
tWP	WE Pulse Width	0.5	tCK
tDS	Data Setup Time	0.75	tCK
tDH	Data Hold Time	0.25	tCK
tWC	Write Cycle Time	1	tCK
tWH	WE High Hold Time	0.5	tCK
tWP	WE Low Hold Time	0.5	tCK
tRC	Read Cycle Time	1	tCK
tRP	RE Pulse Width	0.5	tCK
tREH	RE High Hold Time	0.5	tCK

Figure 23: Command Latch Cycle

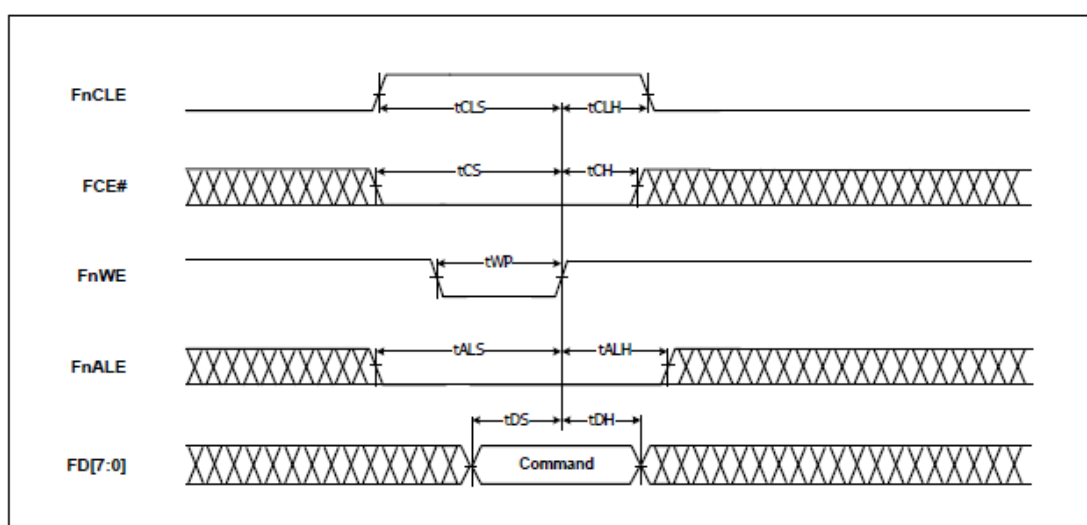


Figure 24: Address Latch Cycle

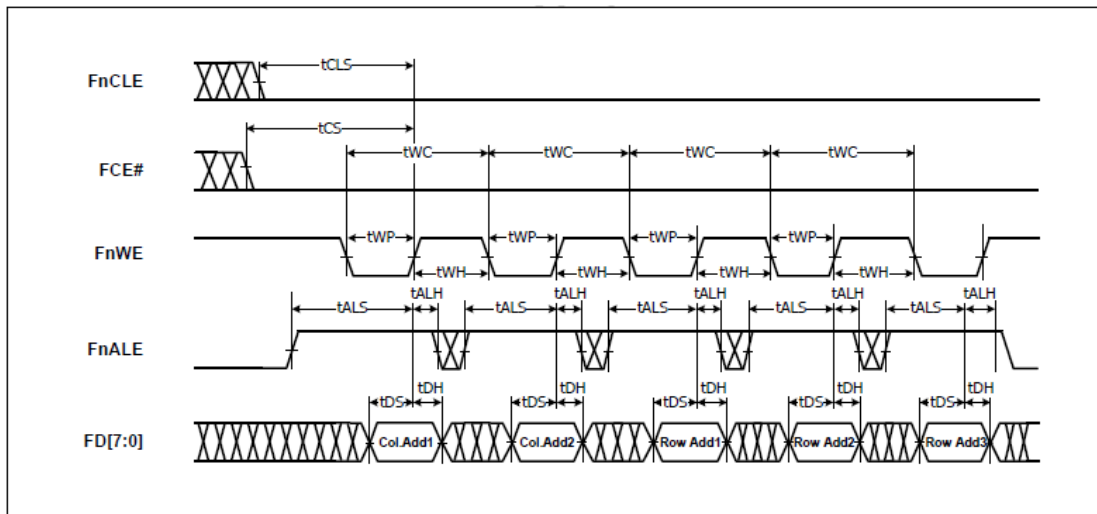
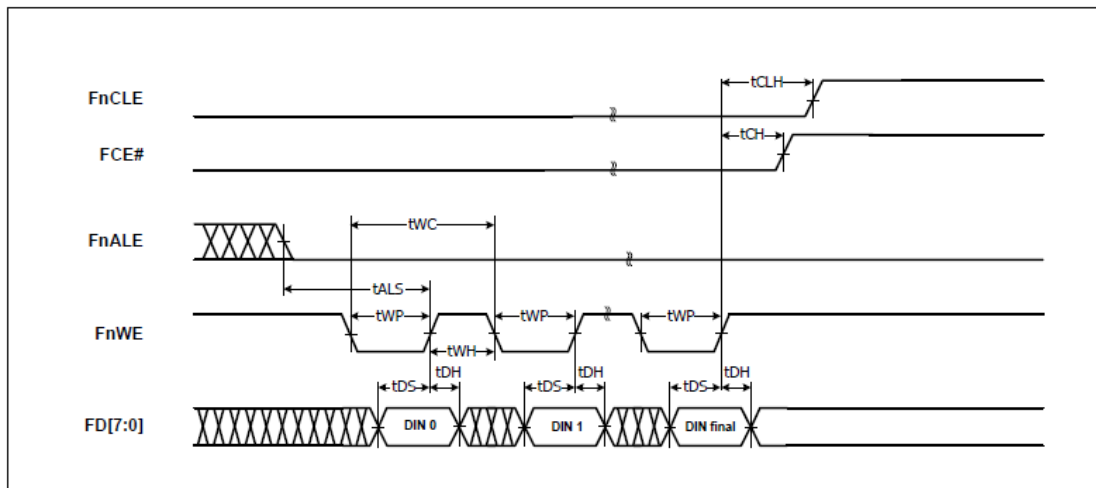


Figure 25: Input Data Latch Cycle



5.4 Power Consumption (typical)

Operation (Read/Write): 110mA/90mA (UDMA6)

Idle: 5mA

Sleep (Partial/Slumber): 5mA/7mA (typ. /max.)

6. Reliability Specification

Item	Features
Operating Temperature	-40°C to +85°C
Storage Temperature	-50°C to +95°C
Humidity	5-95%
Vibration	20G(7-2000HZ)
Shock	2,000G(@0.3ms half sine wave)

6.1 Wear-leveling

Renice X5 2.5" IDE SSD support both static and dynamic wear-leveling. These two algorithms guarantee all type of flash memory at same level of erase cycles to improve lifetime limitation of NAND based storage

6.2 Endurance

Write endurance: >8 years @ 100GB write/ day (8GB SLC)

Read endurance: unlimited

6.3 H/W ECC for NAND Flash

Hardware BCH ECC capable of correcting errors up to 72-bit/1KB

6.4 MTBF

MTBF (Mean Time between Failures) of Renice X5 2.5" PATA IDE SSD: 3,000,000 hours

Data retention at 25°C of Renice SSD: >10 years

6.5 Over voltage and inrush current protection

The over voltage and inrush current protection mechanism of Renice X5 2.5" PATA IDE SSD is to deploy a protect circuitry on Device Power In. Once the current or voltage is exceeded, it will be pulled down to the normal value in very short time to protect the drive.

7. Software Interface

Renice X5 2.5" PATA IDE SSD supports the SMART (Self-Monitoring, Analysis and Reporting Technology) command set and defines some vendor-specific data to report spare/bad block numbers. Detailed SMART commands and data structure will be updated in a later Data Sheet version.

7.1 SMART Feature Set

Renice X5 2.5" PATA IDE SSD supports the SMART (Self-Monitoring, Analysis and Reporting Technology) command set and defines some vendor-specific data to report spare/bad block numbers in each memory management unit.

SMART Feature Register Values

Value	Command	Value	Command
D0h	Read Data	D5h	Reserved
D1h	Read Attribute Threshold	D6h	Reserve
D2h	Enable/Disable Autosave	D8h	Enable SMART Operations
D3h	Save Attribute Values	D9h	Disable SMART Operations
D4h	Execute OFF-LINE Immediate	DAh	Return Status

7.2 SMART Data Structure

The following 512 bytes make up the device SMART data structure. Users can obtain the data using the "Read Data" command (D0h).

SMART Data Structure

Byte	F / V	Description
0 - 1	X	Revision code
2 - 361	X	Vendor specific (see 4.2.2)
362	V	Off-line data collection status
263	X	Self-test execution status byte
364-365	V	Total time in seconds to complete off-line data collection activity
366	X	Vendor specific

367	F	Off-line data collection capability
368-369	F	SMART capability
370	F	Error logging capability • 7-1 Reserved • 0 1 = Device error logging supported
371	X	Vendor specific
372	F	Short self-test routine recommended polling time (in minutes)
373	F	Extended self-test routine recommended polling time (in minutes)
374	F	Conveyance self-test routine recommended polling time (in minutes)
375-385	R	Reserved
386-395	F	Firmware Version/Date Code
396-399	R	Reserved
400-406	F	'Chips information'
407-511	R	Reserved

Notes:

1. F = content (byte) is fixed and does not change.
2. V = content (byte) is variable and may change depending on the state of the device or the commands executed by the device.
3. X = content (byte) is vendor specific and may be fixed or variable.
4. R = content (byte) is reserved and shall be zero.

7.3 SMART Attributes

The following table defines the vendor specific data in byte 2 to 361 of the 512-byte SMART data.

SMART Data Vendor-Specific Attributes

Attribute ID (hex)	Raw Attribute Value						Attribute Name
01	LSB	MSB	00	00	00	00	Read error rate
05	LSB	MSB	00	00	00	00	Reallocated sector count
0C	LSB	MSB	00	00	00	00	Power cycle count
A1	LSB	MSB	00	00	00	00	Number of valid spare block
A2	LSB	MSB	00	00	00	00	Number of child pair

A3	LSB	MSB	00	00	00	00	Number of initial invalid block
A4	LSB			MSB	00	00	Number of total erase count
A5	LSB			MSB	00	00	Maximum erase count
A6	LSB			MSB	00	00	Minimum erase count
A7	LSB			MSB	00	00	Average erase count
C0	LSB			MSB	00	00	Power-off retract count
C7	LSB	MSB	00	00	00	00	UDMA CRC error count
F1	LSB					MSB	Total LBAs written (each write unit = 32MB)
F2	LSB					MSB	Total LBAs read (each read unit = 32MB)

8. PATA Host ID table

The Identify Device command enables the host to receive parameter information from the Renice X5 2.5" PATA IDE SSD. This command has the same protocol as the Read Sector(s) command. The parameter words in the buffer have the arrangement and meanings defined in the following Table.

ID Table Information

Word Address	Default Value	Total Bytes	Data Field Type Information
0	044Ah	2	General configuration
1	XXXXh	2	Default number of cylinders
2	0000h	2	Reserved
3	00XXh	2	Default number of heads
4	0000h	2	Obsolete
5	0240h	2	Obsolete
6	XXXXh	2	Default number of sectors per track
7-8	XXXXh	4	Number of sectors per card (Word 7 = MSW, Word 8 = LSW)
9	0000h	2	Obsolete
10-19	XXXXh	20	Serial number in ASCII (Right justified)
20	0002h	2	Obsolete
21	0002h	2	Obsolete
22	0004h	2	Obsolete
23-26	XXXXh	8	Firmware revision in ASCII. Big Endian Byte Order in Word
27-46	XXXXh	40	Model number in ASCII (Left justified). Big Endian Byte Order in Word
47	8001h	2	Maximum number of sectors on Read/Write Multiple command
48	0000h	2	Reserved
49	0F00h	2	Capabilities

50	0000h	2	Capabilities
51	0200h	2	PIO data transfer cycle timing mode
52	0000h	2	Obsolete
53	0007h	2	Field validity
54	XXXXh	2	Current numbers of cylinders
55	XXXXh	2	Current numbers of heads
56	XXXXh	2	Current sectors per track
57-58	XXXXh	4	Current capacity in sectors (LBAs) (Word 57 = LSW, Word 58 = MSW)
59	0000h	2	Multiple sector setting
60-61	XXXXh	4	Total number of sectors addressable in LBA Mode
62	0000h	2	Reserved
63	0007h	2	Multiword DMA transfer. In PCMCIA mode this value shall be 0h.
64	0003h	2	Advanced PIO modes supported
65	0078h	2	Minimum Multiword DMA transfer cycle time per word. In PCMCIA mode this value shall be 0h.
66	0078h	2	Recommended Multiword DMA transfer cycle time. In PCMCIA mode this value shall be 0h.
67	0078h	2	Minimum PIO transfer cycle time without flow control
68	0078h	2	Minimum PIO transfer cycle time with IORDY flow control
69-79	0000h	22	Reserved
80	0100h	4	Major version number (ATAPI-8)
81	0000h		Minor version number
82	7028h	2	Command sets supported 0
83	5000h	2	Command sets supported 1
84	4000h	2	Command sets supported 2
85	0000h	2	Command sets enabled 0
86	0000h	2	Command sets enabled 1
87	0000h	2	Command sets enabled 2
88	007Fh	2	Ultra DMA mode supported and selected
89	0000h	2	Time required for Security erase unit completion
90	0000h	2	Time required for Enhanced security erase unit completion
91	0000h	2	Current Advanced power management value
92	0000h	2	Master Password revision code
93	604Fh 6F00h 603Fh	2	. Hardware reset result (Master) . Hardware reset result (Slave) . Hardware reset result (Master w/ slave present)
94-127	0000h	68	Reserved
128	0000h	2	Security status
129-159	0000h	62	Vendor unique bytes
160	0000h	2	Power requirement description
161	0000h	2	Reserved

162	0000h	2	Key management schemes supported
163	0000h	2	Advanced True IDE Timing Mode Capability and Setting
164	0000h	2	Advanced PCMCIA I/O and Memory Timing Mode Capability and Setting
165-175	0000h	22	Reserved
176-255	0000h	160	Reserved

9. Ordering Information

Valid Combinations

Capacities/Flash type	Industrial Temp
16GB/MLC	RIM016-PX52
32GB/MLC	RIM032- PX52
64GB/MLC	RIM064- PX52
128GB/MLC	RIM128- PX52
8GB/SLC	RIS008- PX52
16GB/SLC	RIS016- PX52
32GB/SLC	RIS032- PX52
64GB/SLC	RIS064- PX52
128GB/SLC	RIS128- PX52

10. Product Part Number Naming Rule

